

## **PFR-208** Title:F5 SCM sensor connected during magnetics test

degauss				
Assembly : Instruments			SubAssembly : SCM	
Component : SCM Preamp		Units Affected:	Units fixed:	
Originator: Michael Ludlam		0 0 0 0 0 x 0	0 0 0 0 x 0	
Organization: SSL			Date: 13 <sup>th</sup> September 2006	
Phone: 510-642-7732			Email : mludlam@ssl.berkeley.edu	
<b>Failure Occurred During (Check one</b> $$				
$\Box$ Functional test x Qualification test $\Box$ S/C Integration $\Box$ Launch operations $\Box$ Other				
<b>Environment</b> w	when failure occurred:	:		
x Ambient	□ Vibration		Shock	□ Acoustic
□ Thermal	□ Vacuum		Thermal-Vacuum	□ EMI/EMC
Problem Description				
During the EM5 DC Magnetics testing at IPL the SCM sensor was not disconnected from the SCM preamp				

During the FM5 DC Magnetics testing at JPL the SCM sensor was not disconnected from the SCM preamp during deperming as required in the procedure.

## **Analyses Performed to Determine Cause**

Analysis was conducted for the applied field of 15 Gauss at 0.3Hz to see if it could have damaged the SCM preamp. The applied voltage to the SCM preamp was calculated to be 2V, the maximum input voltage the preamp can sustain is 45V.

A functional test of the preamp with the feedback plug attached was conducted and the results showed nominal behavior.

## **Corrective Action/ Resolution**

No damage was done to the SCM preamp by no unplugging it from the SCM sensor during the deperming operation. However, personnel were made aware of the requirement and the procedure was reviewed to ensure future tests included the sensor disconnected from the preamp during DC magnetics deperming. This PFR is closed.

Acceptance:	
MAM: Ron Jackson	MSE: Ellen Taylor
PM: Peter Harvey	; Cognizant Engineer

Date of Closure\_